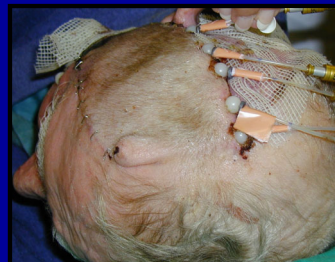
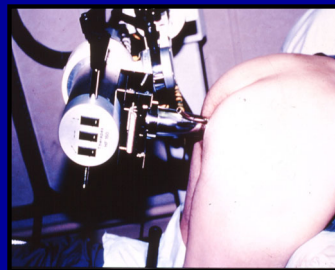


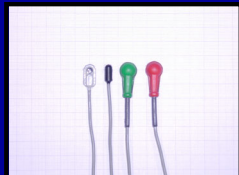
Summary - Problem P7: Energy Response Characteristics of a MOSFET Radiation Detector

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The City University
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- National requirements to perform *in vivo* patient dosimetry (eg Council Directive 97/43/euratom, UK cancer standards, etc)
- Should form part of QA procedures of an oncology department
- Ergo a need for simple high-fidelity system
- Reality: - no system exists for brachytherapy QA



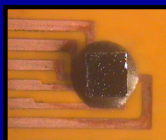
- Typical *in vivo* dosimetry uses:
- Diodes and or TLDs placed on the patient's body



- TLDs can't provide time resolution and require post processing

- True *in vivo* dosimetry
- Spatial and temporal resolution : stepped brachytherapy
- Integrated response
- Fit inside 1.5 mm ID tube
- Integrated software and hardware design methodology
- Permit repeated post Tx readout without data corruption

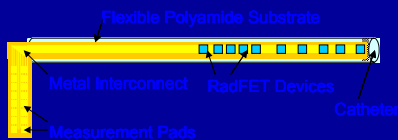
- Develop non-encapsulated semiconductors (MOSFETs)



- Use micro-electronics fabrication processes

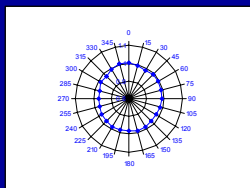
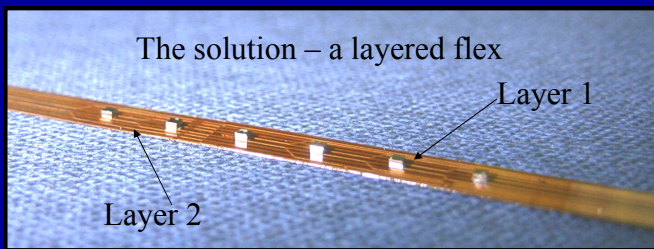


- Mount detectors on flexible polyamide to produce array

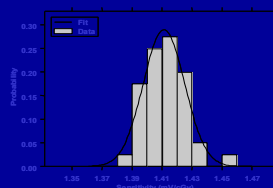


We need four interconnects for each RadFet – we also have an onboard diode so we need an extra line for this

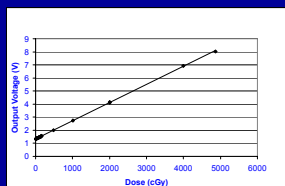
➤ a total of 51 interconnects!



Anisotropy

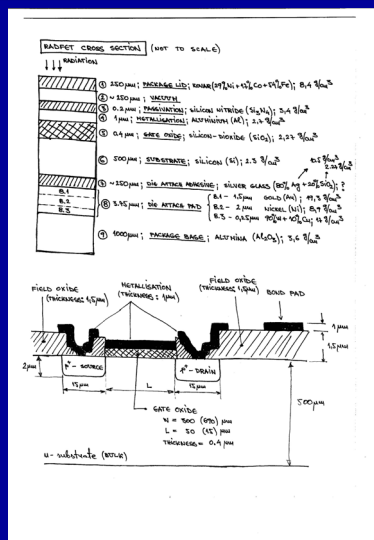
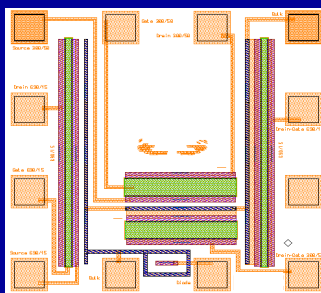
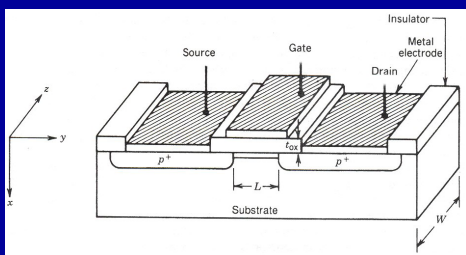
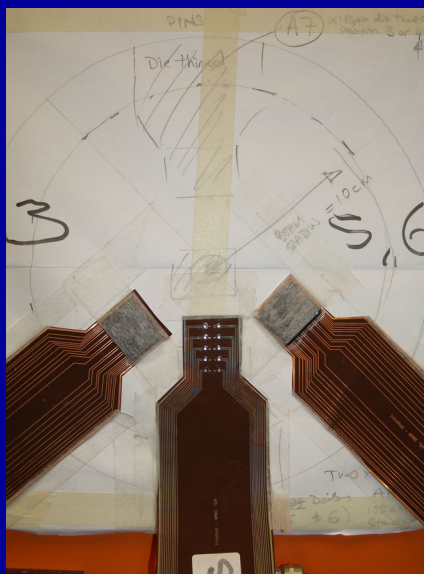
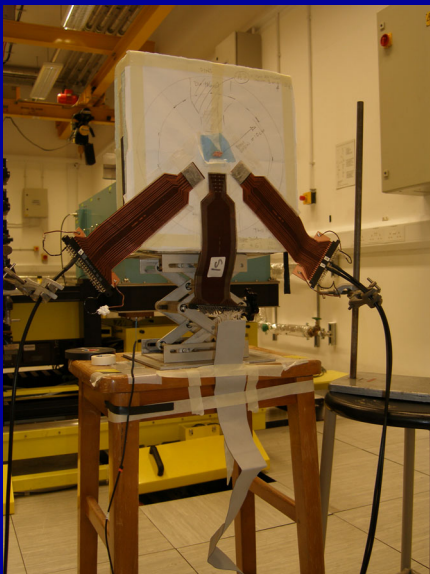


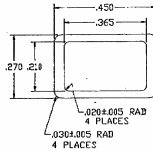
Inter-device sensitivity



Energy response

Linearity





- NOTES
1. MAT'L : MOVAR OR ALLOY 42
 2. PLATING : 1st LAYER 50/350 MICROINCHES NI
 3. PLATING : 2nd LAYER Au
 - 3rd LAYER 50/350 MICROINCHES NI
 - 4th LAYER 25 MICROINCHES MINIMUM Au
- NOTES : TOTAL NICKEL LAYERS SHALL NOT EXCEED 450 MICROINCHES AND THE SUM OF BOTH GOLD LAYERS SHALL BE 50 MICROINCHES MINIMUM.
3. PREFORM - 80% ±1% Au
20% Sn
 4. FLATNESS : ONE MIL (.001) MAXIMUM PER 1/2" T.I.R
 5. TOLERANCES TO BE (XXX) 3 PLACES ±.003 UNLESS OTHERWISE NOTED
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NOTES

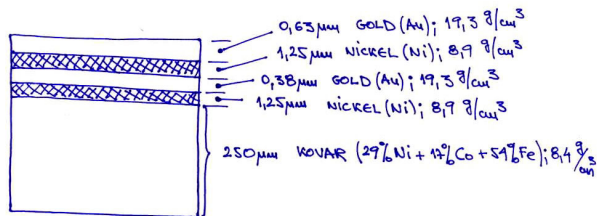
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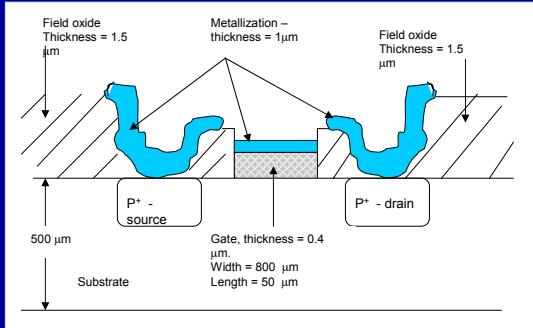
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LAYER ① (PACKAGE LID) - MORE DETAILED DESCRIPTION





Region 1: 250 μm lid – 29% Ni, 17% C0, 54% Fe

Region 2: 250 μm vacuum

Region 3: 0.2 μm thick passivation – Si₃N₄

Region 4: 1 μm thick aluminium contact

Region 5: 0.4 μm thick gate oxide – SiO₂

Region 6: 500 μm thick silicon substrate - Si

Region 7: 250 μm adhesive – 80% Ag, 20% SiO₂

Region 8: 1.5 μm Au attach pad A

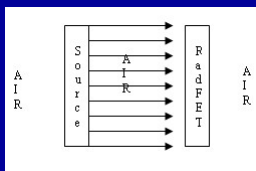
Region 9: 2 μm Ni attach pad B

Region 10: 0.2 mm attach pad C - 90% W, 10% Cu

Region 11: 1000 μm Al₂O₃, base

The problems:

1 Calculate the energy response function (for capped and uncapped systems)

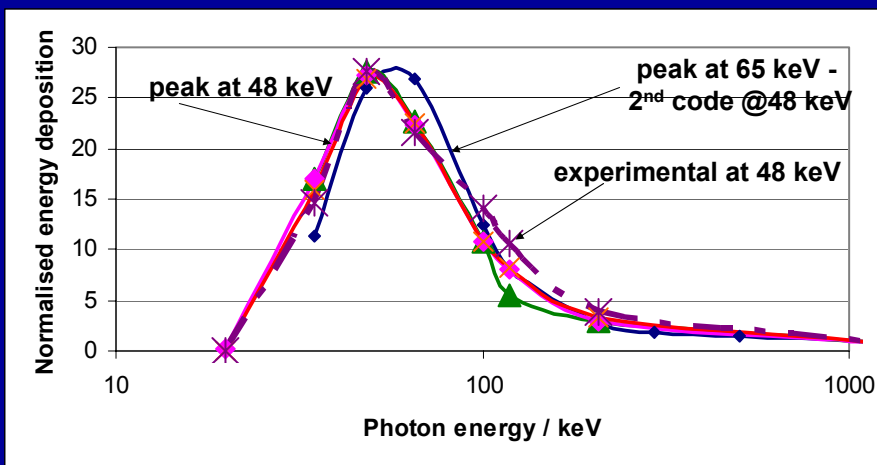
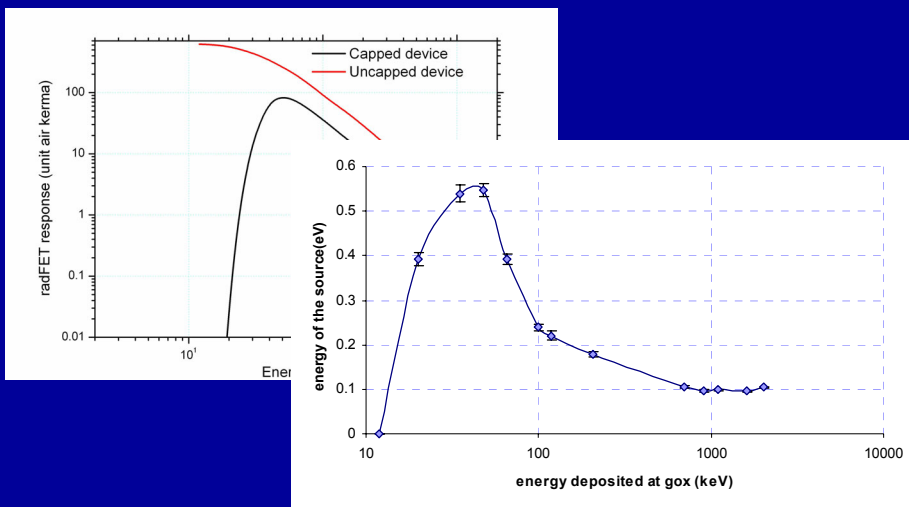


2 Consider the effects of uncertainties in the composition of the device:

- 20% in thickness of region 1
- 20% in Ni proportion of region 1
- 20% in Ag in region 7
- 200% underestimate of region 8 thickness
- sensitivity to lateral extent

	Participant A	Participant B	Participant C	Participant D
MCNPX		X	X	
PENELOPE				X
GEANT 4	X			
FLUKA	X			
FOTELP		X		

	Participant A	Participant B	Participant C	Participant D
Q1a	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$
Q1b	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$
Q2a	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$
Q2b	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$
Q2c	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$
Q2d	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$
Q2e	$X \pm \sigma_{\text{rand}}$	$X \pm \sigma_{\text{rand}}$	NO	NO





Uncertainty Assessment in Computational Dosimetry: A comparison of Approaches



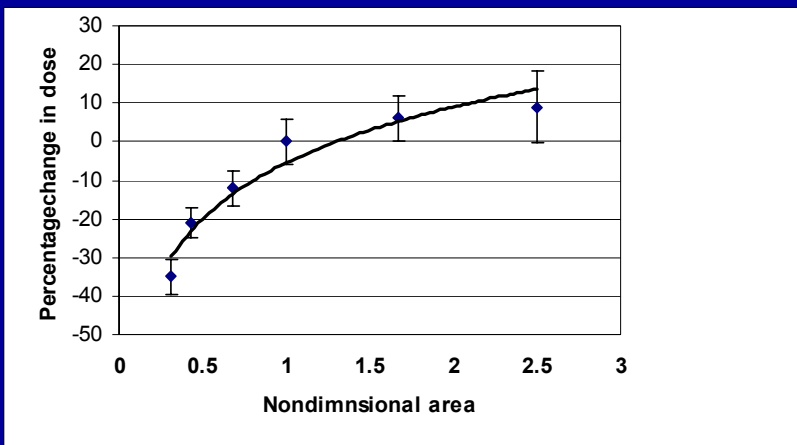
	Participant A	Participant B	Participant C	Participant D
MCNPX		48 keV	48 keV	
PENELOPE				48 keV
GEANT 4	48 keV			
FLUKA	65 keV			
FOTELP		48 keV		



Uncertainty Assessment in Computational Dosimetry: A comparison of Approaches



	Participant A	Participant B	Participant C	Participant D
MCNPX		27.65±0.06	27.23±1.17	
PENELOPE				26.81±2.17
GEANT 4	26.74±1.65			
FLUKA	26.82±1.37			
FOTELP		26..9±0.11		



	Participant A	Participant B	Participant C	Participant D
Uncertainty budget	Yes	No	No	No

Components of uncertainty budget from problem specification

- Code statistics
- Uncertainty in layer thickness
- Uncertainty in composition
- Uncertainty in kerma calculation
- Uncertainty in energy of maximum
- Uncertainty in iso energy
- Geometrical truncation
- Cross-sections
- Code space
- etc

Simple assumption - independent

Components of uncertainty budget from problem specification

	Variation
Stats	3 % @ conv.
Lid thickness	7% @10% change
Ni fraction	1% < stats
Ag fraction	nil
Geom trunc.	10 %
X-sections	assume 5%
Codes	4%

Mean value @ peak 48 keV

$27.42_{-14}^{+14}\%$

Much higher than the 1 - 3% statistical uncertainty usually reported !

If we ignore all but lid and geometric truncation - 12 %